



Information Disclosure Statement
USSN 10/719,008
October 22, 2004
Page 4

BEST AVAILABLE COPY

Form PTO-1449 (Modified)	ATTY DOCKET NO. B-5309 621525-5	U.S. SERIAL NO. 10/719,008
LIST OF PATENTS AND PUBLICATIONS STATEMENT	APPLICANTS Keiji YADA, et al.	
	FILING DATE November 21, 2003	GROUP not yet assigned

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	ISSUE DATE	NAME	CLASS	SUB-CLASS	FILING DATE or 102(e) DATE IF APPROPRIATE
EMK	5,602,899	2/1997	Larson	378	143	
EMK	6,282,263 B1	8/2001	Arndt et al.	378	138	
EMK	2001/0001010 A1	5/2001	Wilkins	378	43	

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	PUBLICATION DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO
EMK	100 29 840	1/2001	DE			abstract
EMK	0 473 227 A2	3/1992	EP			
EMK	735,943	8/1955	GB			
EMK	duplicate 31 224	6/1974	GB			
EMK	01/15192 A1	3/2001	WO			
EMK	03/065772 A2	8/2003	WO			

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

--

EXAMINER <i>Dorothy Kearney</i>	DATE CONSIDERED <i>7/16/05</i>
------------------------------------	-----------------------------------

EXAMINER: Initial is reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



Information Disclosure Statement
USN 10/719,008
September 1, 2004
Page 4

Form PTO-1449 (Modified)	ATTY DOCKET NO. B-5309 621525-5	U.S. SERIAL NO. 10/719,008
LIST OF PATENTS AND PUBLICATIONS STATEMENT	APPLICANTS Keiji YADA, et al.	
	FILING DATE November 21, 2003	GROUP not yet assigned

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	ISSUE DATE	NAME	CLASS	SUB- CLASS	FILING DATE or 102(e) DATE IF APPROPRIATE
ENK	10/719,887		Yada et al.			11/21/2003

FOREIGN PATENT DOCUMENTS

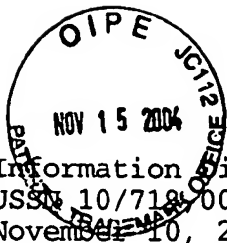
	DOCUMENT NUMBER	PUBLICATION DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO
ENK	2004-138460	5/2004	JP			Abstract and partial translation

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

ENK	Nixon, W.C., "High-Resolution X-Ray Projection Microscopy," Proc. Roy. Soc., A232, pp. 475-485 (1960).
ENK	Yada, K., et al., "Development of Projection X-Ray Microscopy and Its Biological Applications," Bulletin of Aomori Public College, Vol. 1, pp. 2-13 (1996).
ENK	Yada, K., et al., "Development of Soft X-Ray Microscopy," Biophysics, Vol. 33, No. 4, pp. 8-16 (1980).
ENK	Yada, K., et al., "High-Resolution Projection X-Ray Microscopy," Multidimensional Microscopy, Chapter 8, pp. 133-150 (1994).
ENK	Yada, K., et al., "Projection X-Ray Shadow Microscopy Using SEM," Bulletin of the Research Institute for Scientific Measurements, Tohoku University, Vol. 29, No. 1, pp. 25-42 (1980).

EXAMINER <i>Elizabeth Looney</i>	DATE CONSIDERED <i>7/16/05</i>
-------------------------------------	-----------------------------------

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 601. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



Information Disclosure Statement
 US 10/719,008
 November 10, 2004
 Page 3

Form PTO-1449 (Modified)	ATTY DOCKET NO. B-5309 621525-5	U.S. SERIAL NO. 10/719,008
LIST OF PATENTS AND PUBLICATIONS STATEMENT	APPLICANTS Keiji YADA, et al.	
	FILING DATE November 21, 2003	GROUP not yet assigned

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	ISSUE DATE	NAME	CLASS	SUB- CLASS	FILING DATE or 102(e) DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	PUBLICATION DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO
DMK	865,050	4/1961	GB			
DMK	2 131 224	6/1984	GB			

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

DMK	Delong, A., et al., "A New Design Of Field Emission Electron Gun With A Magnetic Lens," <i>Optik</i> , Vol. 81, No. 3, pp. 103-108 (1989).
DMK	Mayo, S.C., et al., "X-Ray Phase-Contrast Microscopy and Microtomography," <i>Optics Express</i> , Vol. 11, No. 19, pp. 2289-2302 (September 2, 2003).

EXAMINER <i>Elizabeth Kearney</i>	DATE CONSIDERED <i>7/6/05</i>
--------------------------------------	----------------------------------

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw lines through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.